



UNIVERSITÄT ZU LÜBECK
INSTITUT FÜR TECHNISCHE INFORMATIK



Fault Analysis in Early Design Steps for AI Application

18.11.2021

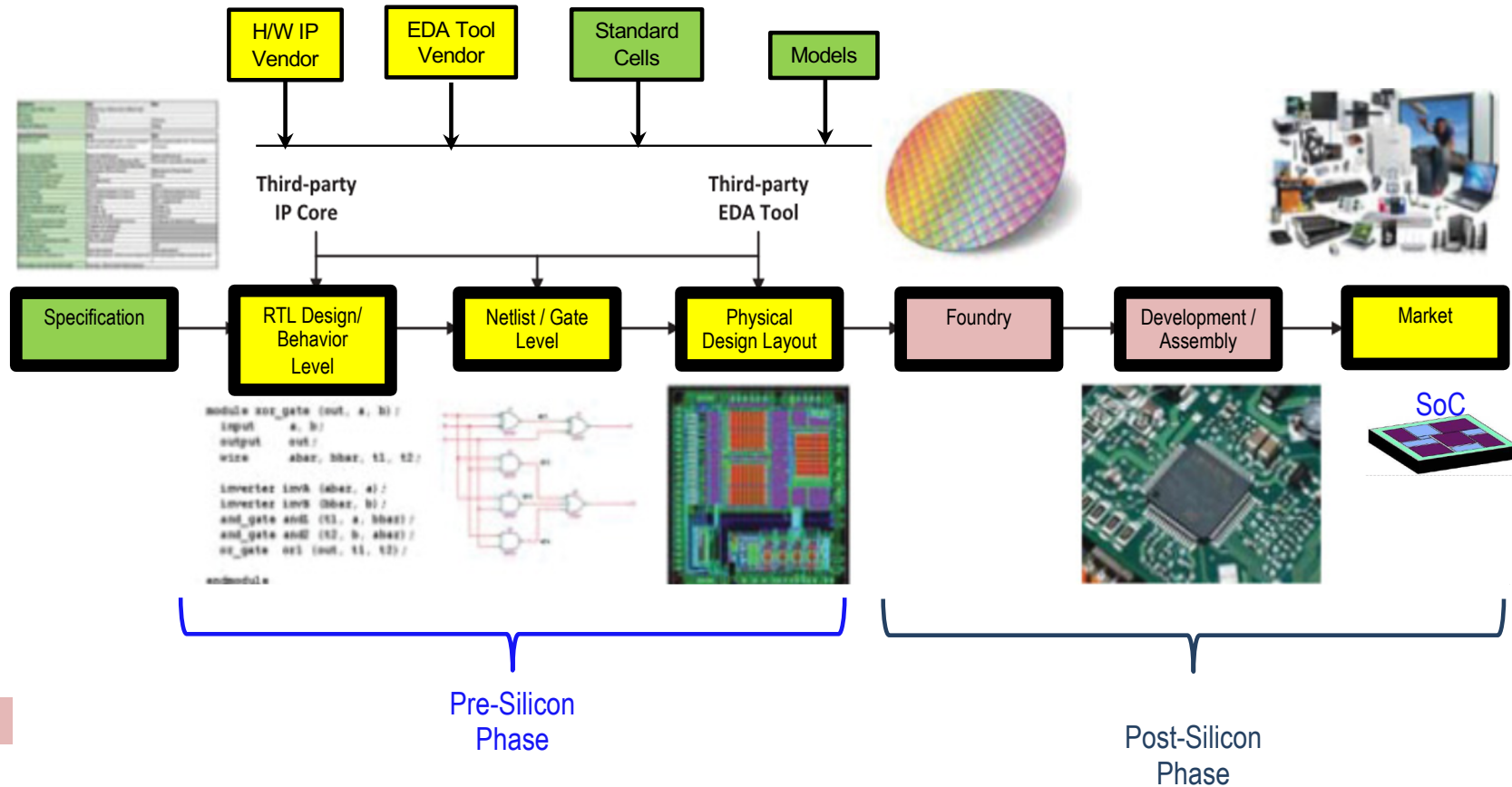
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Outline

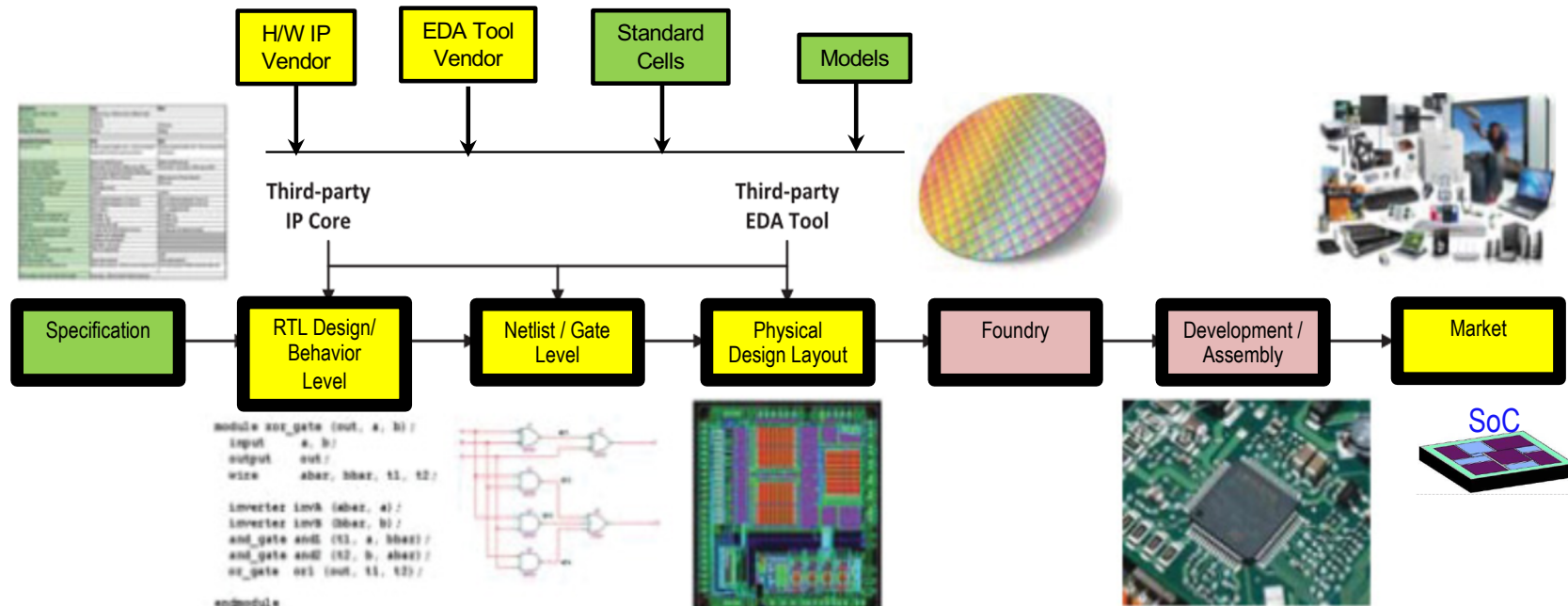
- Semiconductor Supply Chain
- Verification Life Cycle
- Classical EDA Flow
- SystemC model in EDS: Neural Network for XOR function
- Fault Injection and Verification: XOR Trained Model.
- KI-Pro as a Case Studay

Semiconductor Supply Chain (SSC)



[XIA 16]

Verification Life Cycle



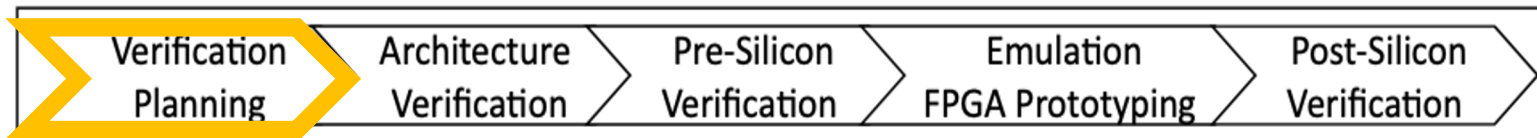
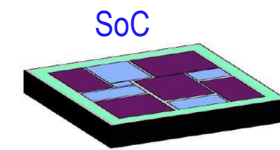
[CHE 17]

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Verification Life Cycle

□ Verification planning

- ❑ starts with the product planning, and continues during the system development phase.
- ❑ defines necessary IPs.
- ❑ defines connection and communication interfaces,
- ❑ determines various power, performance, security, and energy targets

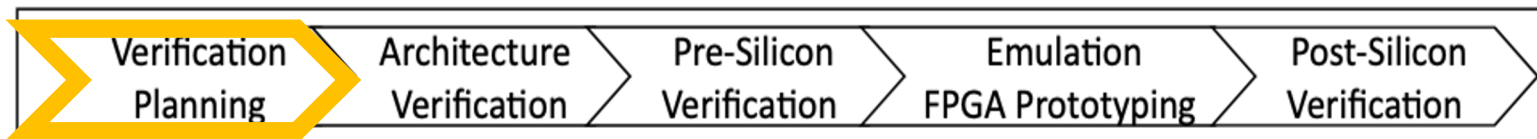
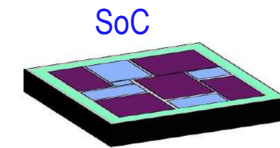


[CHE 17]

Verification Life Cycle

□ Verification planning

- ❑ starts with the product planning, and continues during the system development phase.
- ❑ defines necessary IPs.
- ❑ defines connection and communication interfaces,
- ❑ determines various power, performance, security, and energy targets
- ❑ creates appropriate test plans, test cards, and various monitors, checker, exercisers, etc.

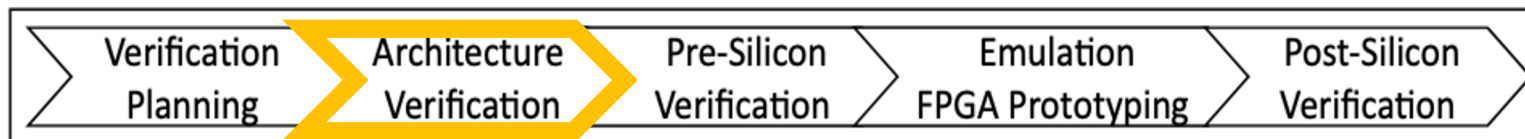
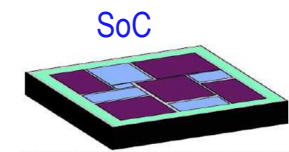


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Verification Life Cycle

□ Architecture verification

- ❑ defines functional parameters of the design (cache size, pipeline depth, etc).
- ❑ determines communication protocols among IPs
- ❑ determines power and performance management schemes, etc



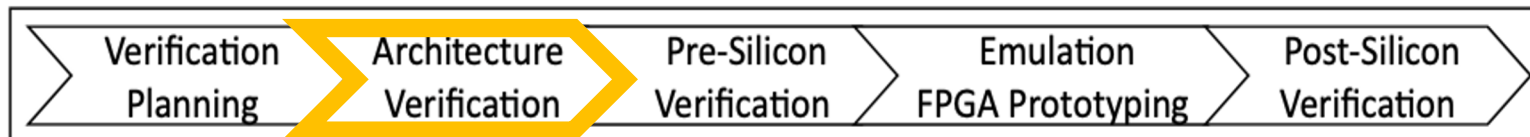
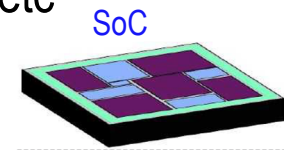
Verification Life Cycle

□ Architecture verification

- ❓ defines functional parameters of the design (cache size, pipeline depth, etc).
- ❓ determines communication protocols among IPs
- ❓ determines power and performance management schemes, etc

□ Most important verification activities:

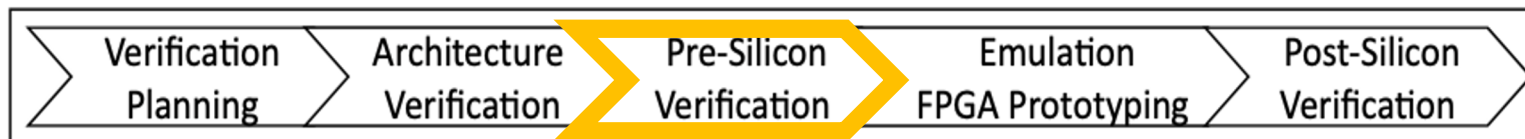
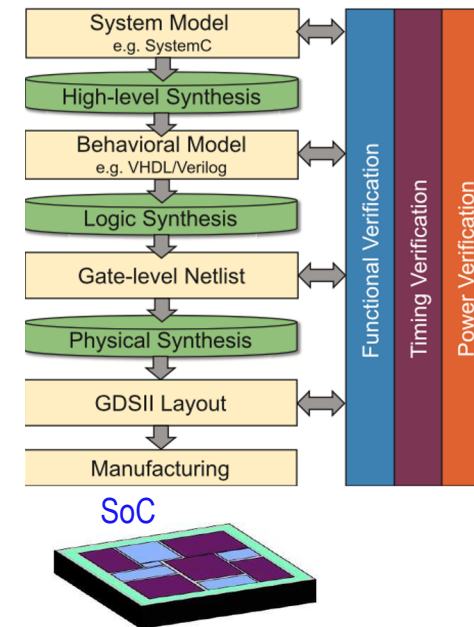
- ❓ Functional verification: to verify communication protocols using system Model.



Verification Life Cycle

□ IP verification team:

- performs the verification of the IP.
- The objective is to ensure that the IP on its own functions as expected.



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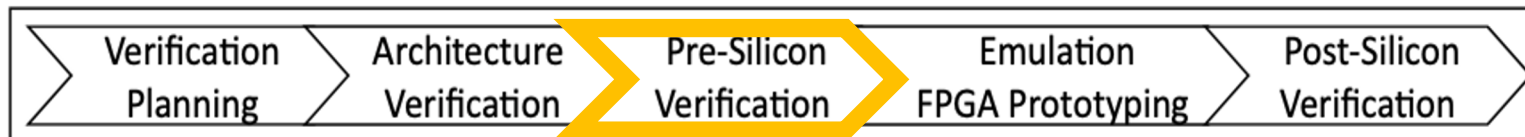
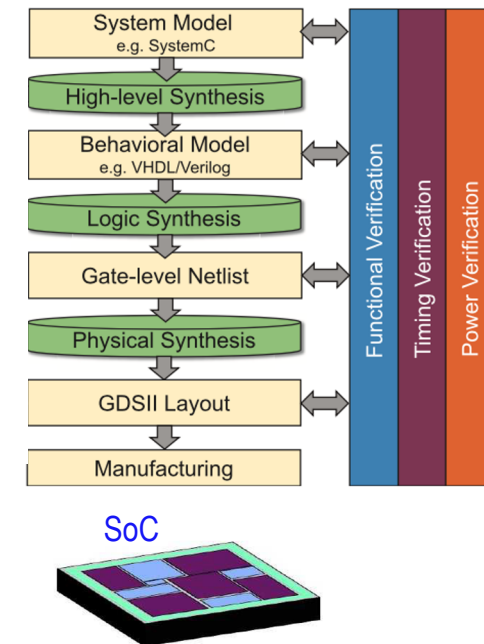
Verification Life Cycle

□ IP verification team:

- performs the verification of the IP.
- The objective is to ensure that the IP on its own functions as expected.

□ SoC team:

- Integrates the IPs into an (evolving) SoC model
- Perform system-level verification.



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Verification Life Cycle

❑ Shrinking verification time

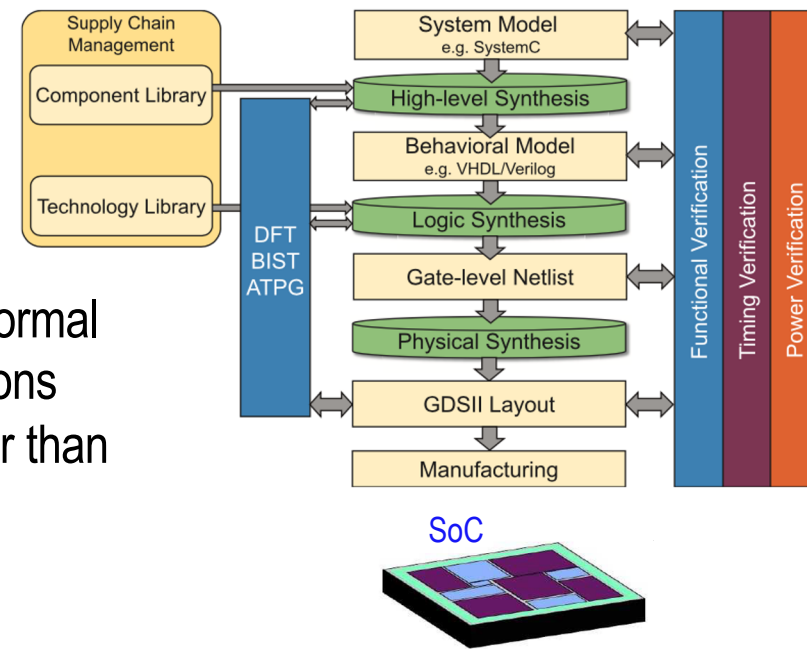
❑ Limited tool scalability

❓ there has been a growing trend in formal methods to target specific applications (e.g., security, deadlock, etc.) rather than a complete proof of functional correctness

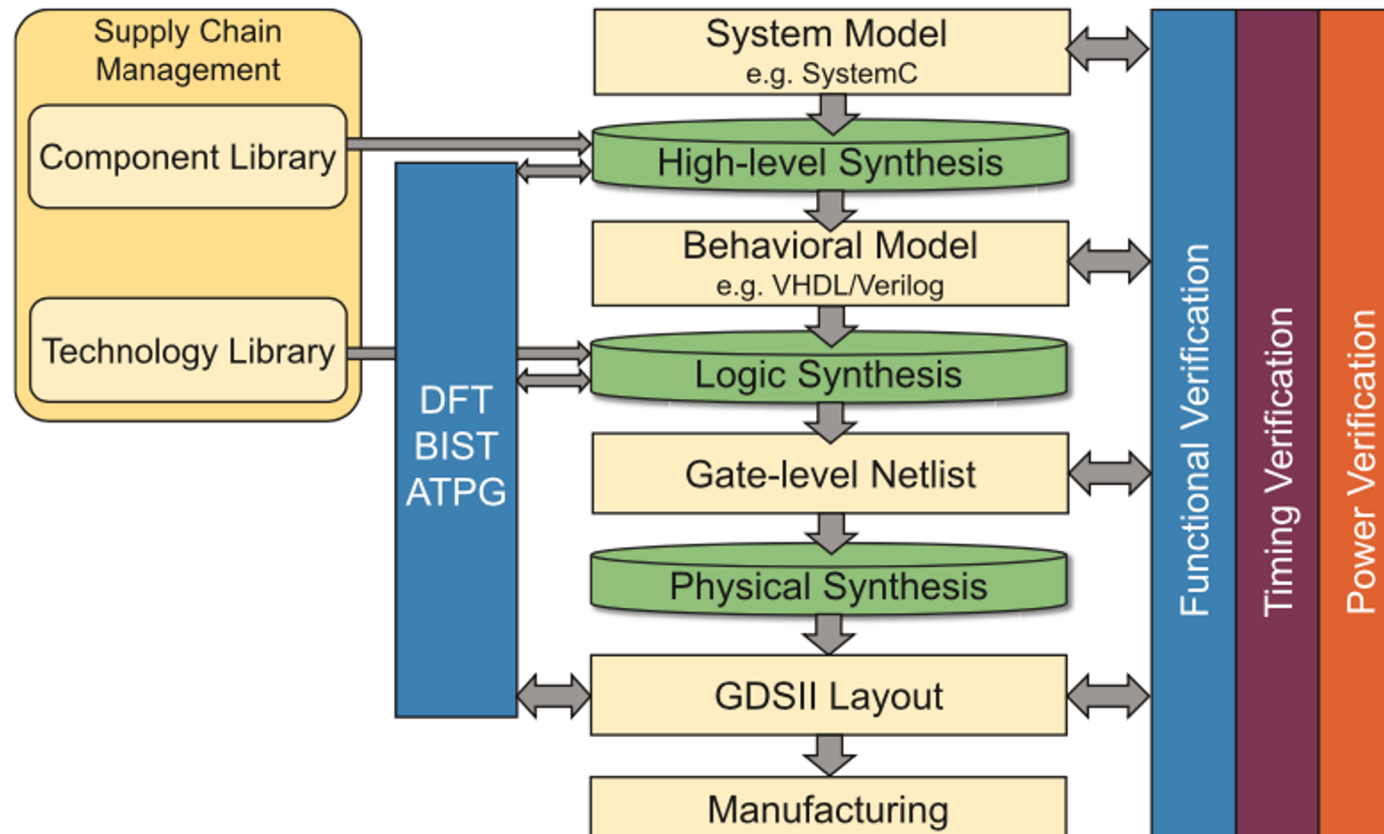
❑ Specification capture

❓ A key challenge in the applicability of verification today is the lack of specifications

❑ Power management challenges



Classical EDA Flow



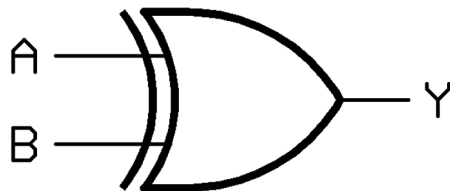
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SystemC model in EDS for AI

- Training of Neural Network for XOR function
- MLP was chosen for its simplicity
- The inference will be run on a SystemC model
- Faults will be injected in different points in the HW (registers)
- Fault propagation behavior will be shown

SystemC model in EDS for AI

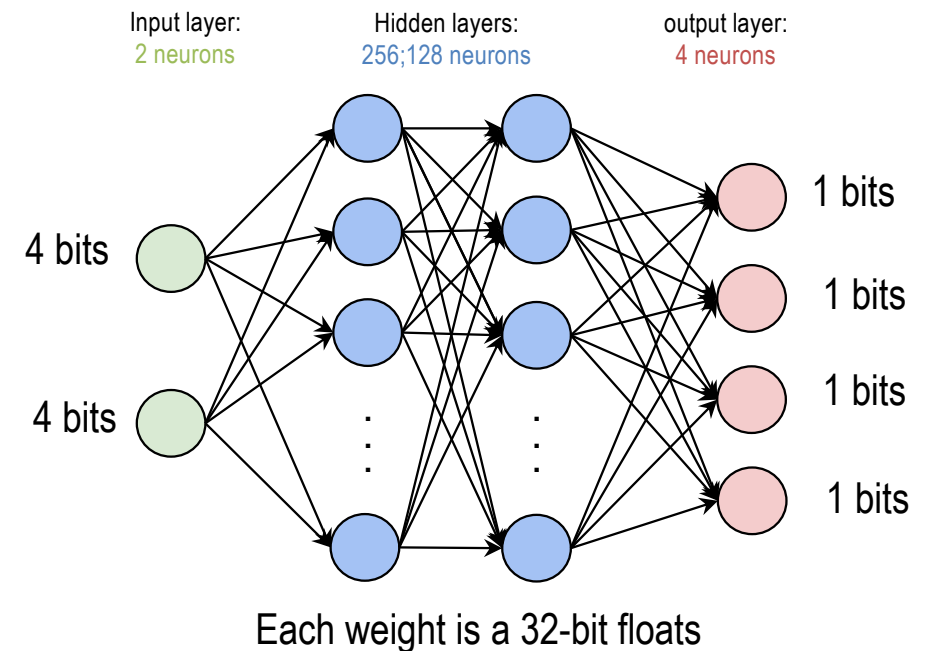
- Neural network will be trained for **XOR gate**.
- Gate input/output have a 4-bit precision each.
- Dataset contains $2^4 \times 2^4 = 256$ samples.
- Training was done in Keras/TensorFlow.



A				B				Y			
0	0	0	0	0	0	0	0	0	0	0	0
0	0	0	0	0	0	0	1	0	0	0	1
0	0	0	0	0	0	1	0	0	0	1	0
⋮				⋮				⋮			
1	1	1	1	1	1	1	1	0	0	0	0

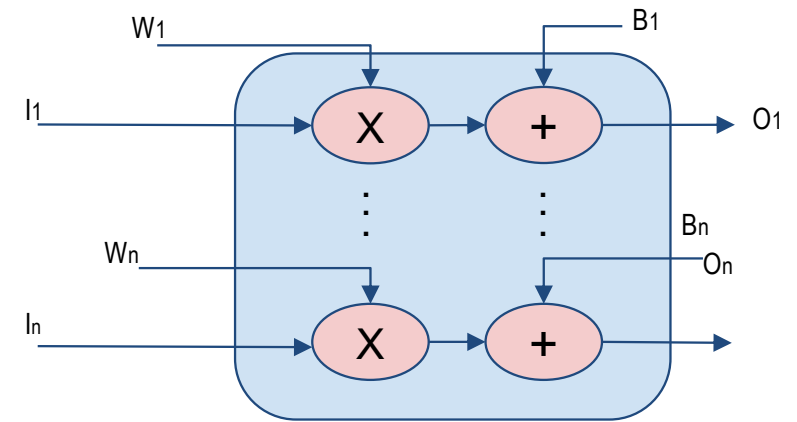
SystemC model in EDS for AI: Neural Network training

- The chosen architecture is 2 neurons at the input with two hidden layers of 256 and 128 neurons and 4 output neurons.
- Rectified Liner (ReLU) as activation function for hidden layers.
- Sigmoid as activation function for output layer.
- Data set not divided into training/test batches because the Neural Network is doing a specific XOR logic on a tiny dataset.
- Overfitting is not a problem for this example.
- Weights are extracted on 32-bit floats

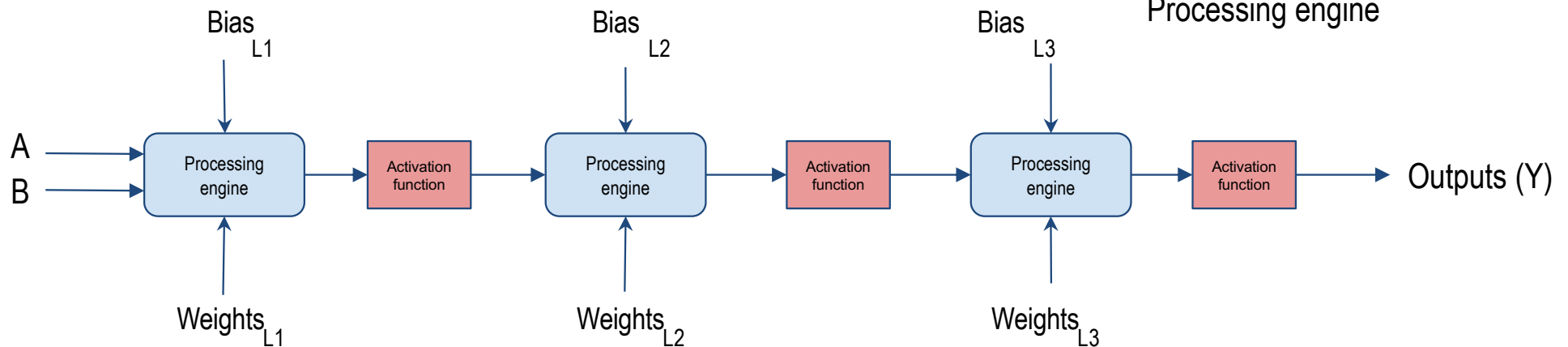


SystemC model in EDS for AI: Model architecture

- Inference was done in SystemC.
- A hardware engine for matrix multiplication is implemented.
- Weights and biases are extracted from the trained model



Processing engine



Fault injection

- Weights are represented on 32-bit floats.
- Faults were injected in random weights at different layers.
- Every time one single fault is injected.
- For one weight, a single fault (one bit-flip) is injected, going from LSB to MSB.

Initial register value: Free Fault



Injection of fault in the first bit



Injection of fault in the second bit



Injection of fault in the last bit

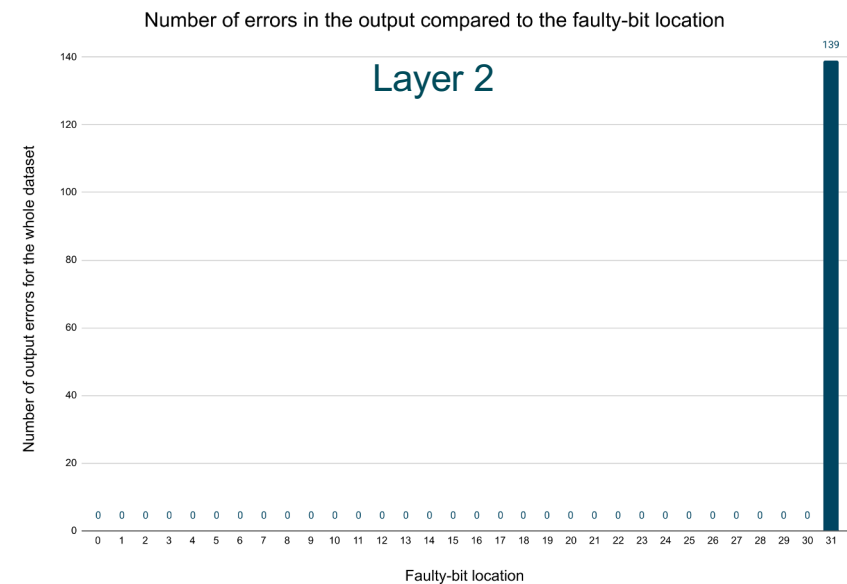
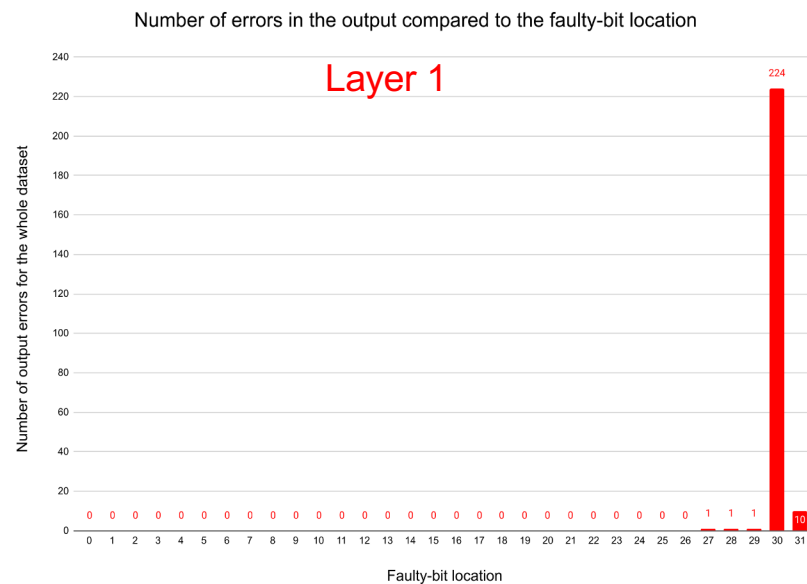


32-bit wide registers

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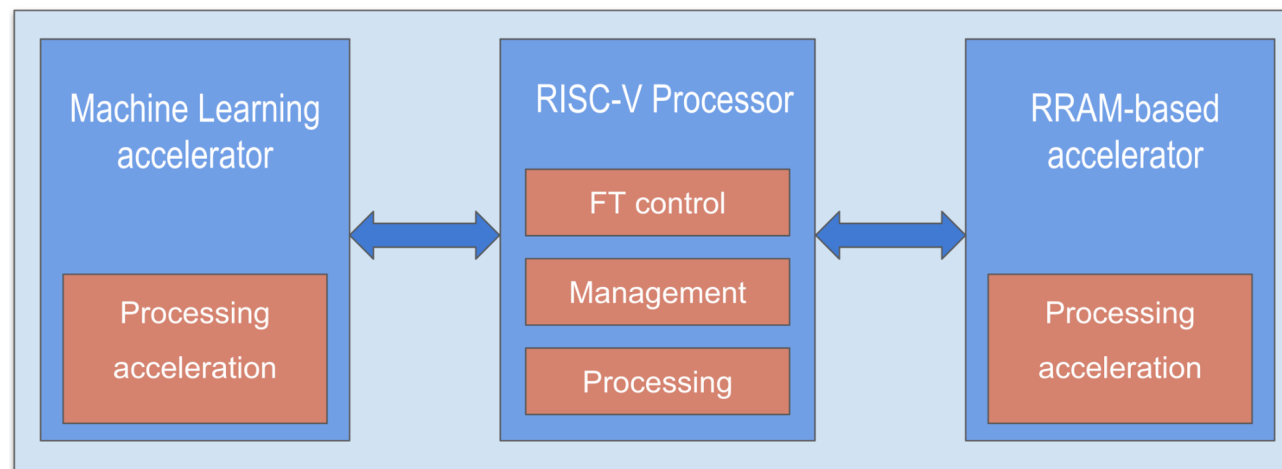
Fault injection

- Injecting faults in the LSB does not lead to errors in the output, the faults are masked.
- Faults injected in the MSB propagate and affect the behavior of the SystemC model.
- Faults injected near the output (at the last layer) are masked.
- The masking effect is present because the weights are float values with 32-bit precision



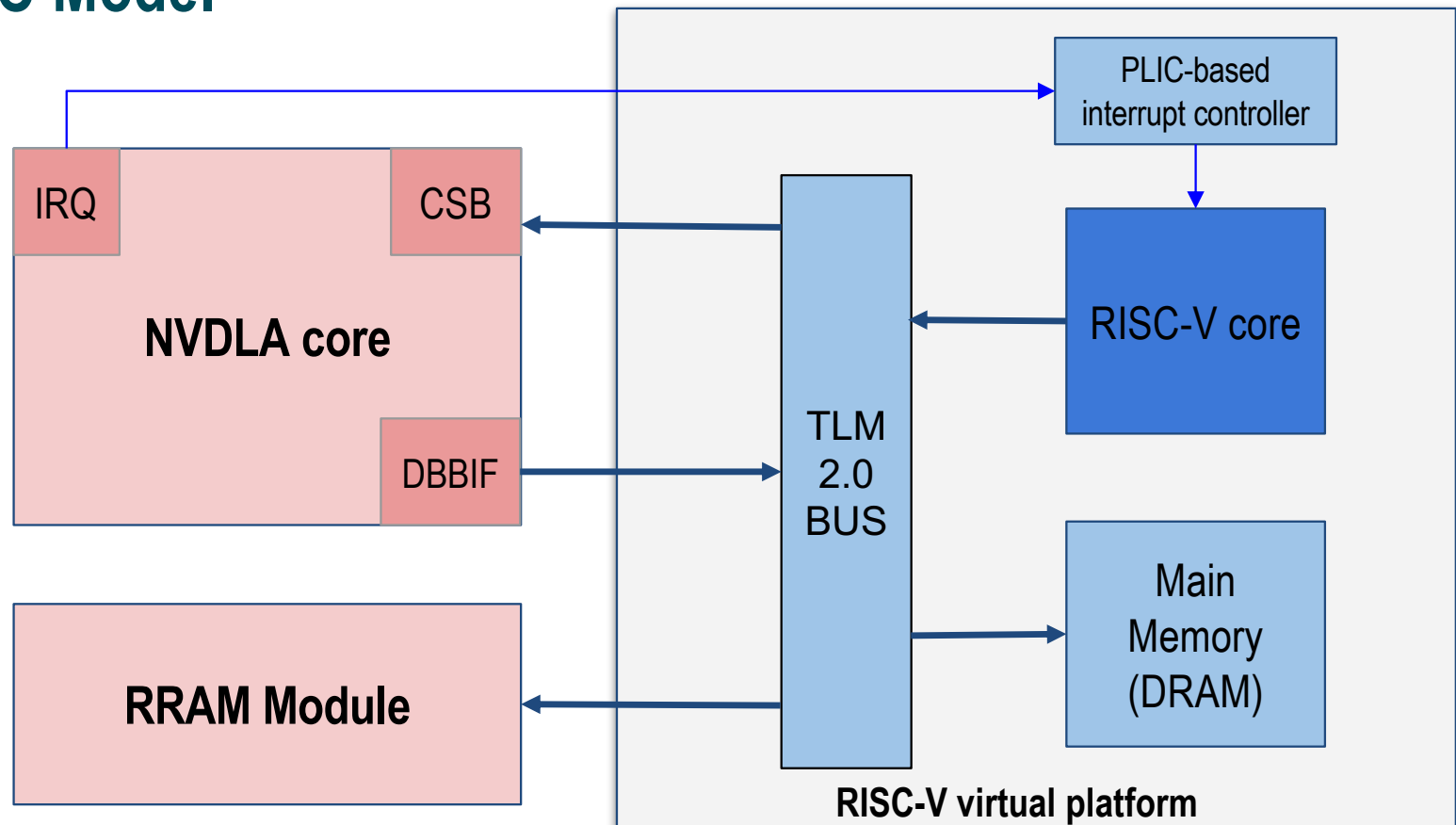
KI-Pro Platform

- RISC-V core based on the RISC-V VP.
- RRAM-based AI accelerator.
- NVIDIA Deep Learning Accelerator as a Machine Learning accelerator



KI-Pro: SystemC Model

The simulation platform uses transaction-based modelling (SystemC/TLM2.0) to achieve the adaptation and interfacing of the different components





References

[KNE 20] J. Knechtel et al., "Towards Secure Composition of Integrated Circuits and Electronic Systems: On the Role of EDA," 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 2020, pp. 508-513, doi: 10.23919/DATE48585.2020.9116483.

[XIA 16] Xiao, Kan, et al. "Hardware trojans: Lessons learned after one decade of research." ACM Transactions on Design Automation of Electronic Systems (TODAES) 22.1 (2016): 1-23.

[CHE 17] Chen, Wen, et al. "Challenges and trends in modern SoC design verification." IEEE Design & Test 34.5 (2017): 7-22.